

1. Record Nr.	UNINA9910140015403321
Titolo	2009 27th IEEE VLSI Test Symposium : proceedings : 3-7 May 2009 Santa Cruz, CA, USA ; VTS 2009
Pubbl/distr/stampa	[Place of publication not identified], : IEEE Computer Society, 2009
ISBN	9781509075676 1509075674
Disciplina	621.39/5
Soggetti	Integrated circuits - Very large scale integration - Testing Electrical Engineering Electrical & Computer Engineering Engineering & Applied Sciences
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Bibliographic Level Mode of Issuance: Monograph